

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
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	Examiner Eric B. Kiss	Art Unit 2192	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0133794 A1	09-2002	Kanapathippillai et al.	716/4
	B US-			
	C US-			
	D US-			
	E US-			
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	H US-			
	I US-			
	J US-			
	K US-			
	L US-			
	M US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
U	"Product Bulletin: Boundary-Scan Logic," 1998, Texas Instruments, pp. 1-8.	
V	"Topic 8 - JTAG Boundary Scan," 1997, 1997 TI Test Symposium, 7 pages.	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.